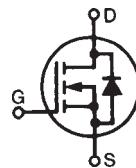


PolarHV™ HiPerFET Power MOSFET ISOPLUS264™

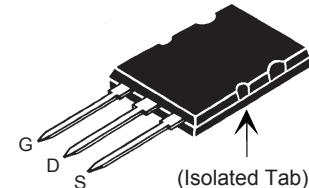
(Electrically Isolated Back Surface)

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

$V_{DSS} = 800$ V
 $I_{D25} = 40$ A
 $R_{DS(on)} \leq 150$ mΩ
 $t_{rr} \leq 250$ ns



ISOPLUS264™ (IXFL)



G = Gate D = Drain
S = Source

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ C$ to $150^\circ C$	800	V	
V_{DGR}	$T_J = 25^\circ C$ to $150^\circ C$; $R_{GS} = 1 M\Omega$	800	V	
V_{GSS}	Continuous	± 30	V	
V_{GSM}	Transient	± 40	V	
I_{D25}	$T_c = 25^\circ C$	40	A	
I_{DM}	$T_c = 25^\circ C$, pulse width limited by T_{JM}	150	A	
I_{AR}	$T_c = 25^\circ C$	30	A	
E_{AR}	$T_c = 25^\circ C$	100	mJ	
E_{AS}	$T_c = 25^\circ C$	5	J	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100$ A/μs, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ C$, $R_G = 2 \Omega$	20	V/ns	
P_D	$T_c = 25^\circ C$	625	W	
T_J		-55 ... +150	°C	
T_{JM}		150	°C	
T_{stg}		-55 ... +150	°C	
T_L	1.6 mm (0.062 in.) from case for 10 s	300	°C	
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1$ mA	t = 1 min t = 1 s	2500 3000	V~
F_c	Mounting force	28..150 / 6.4..30	N/lb	
Weight		5	g	

Symbol	Test Conditions ($T_J = 25^\circ C$, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV_{DSS}	$V_{GS} = 0$ V, $I_D = 3$ mA	800		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 8$ mA	3.0		V
I_{GSS}	$V_{GS} = \pm 30$ V _{DC} , $V_{DS} = 0$		± 200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0$ V		25 3000	μA
$R_{DS(on)}$	$V_{GS} = 10$ V, $I_D = I_T$, Note 1		150	mΩ

Features

- International standard isolated package
- UL recognized package
- Silicon chip on Direct-Copper-Bond substrate
 - High power dissipation
 - Isolated mounting surface
 - 2500V electrical isolation
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect
- Fast intrinsic diode

Advantages

- Easy to mount
- Space savings
- High power density

Symbol Test Conditions

Characteristic Values

(T_J = 25°C, unless otherwise specified)

Min. Typ. Max.

g_{fs}	V _{DS} = 20 V; I _D = I _T , Note 1	35	67	S
C_{iss} C_{oss} C_{rss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	18	nF	
		1200	pF	
		44	pF	
t_{d(on)} t_r t_{d(off)} t_f	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = I _T R _G = 1 Ω (External)	36	ns	
		29	ns	
		110	ns	
		26	ns	
Q_{g(on)} Q_{gs} Q_{gd}	V _{GS} = 10 V, V _{DS} = 0.5 V _{DSS} , I _D = I _T	250	nC	
		90	nC	
		78	nC	
R_{thJC}			0.20	°C/W
R_{thCS}		0.13		°C/W

Source-Drain Diode

Characteristic Values

(T_J = 25°C, unless otherwise specified)

Symbol Test Conditions

Min. Typ. Max.

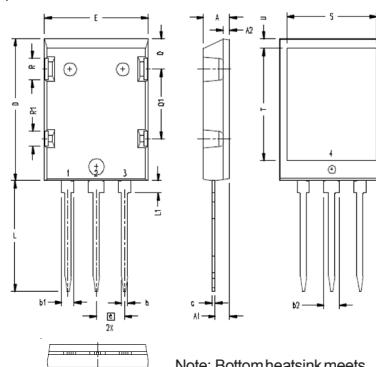
I_s	V _{GS} = 0 V		60	A
I_{SM}	Repetitive		150	A
V_{SD}	I _F = I _S , V _{GS} = 0 V, Note 1		1.5	V
t_{rr} Q_{RM} I_{RM}	I _F = 25A, -di/dt = 100 A/μs V _R = 100V		250	ns
			0.6	μC
			6.0	A

Notes:

1. Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %

Test Current I_T = 30 A

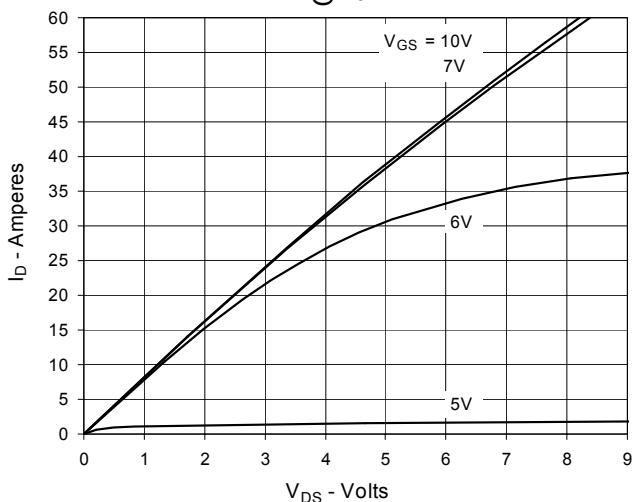
ISOPLUS264 (IXFL) Outline



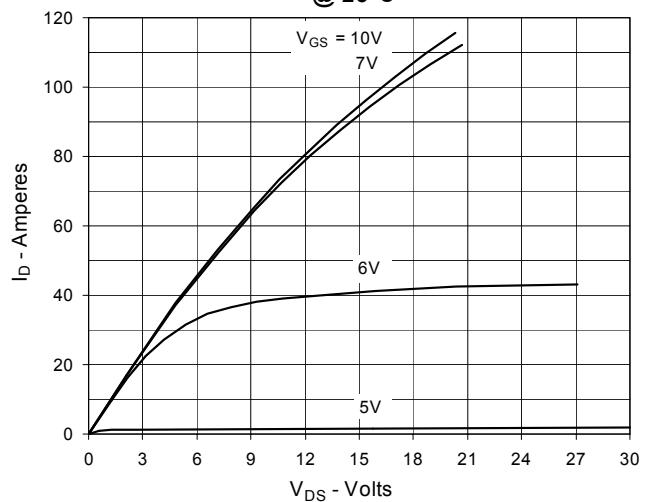
SYN	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.102	.118	2.59	3.00
A2	.046	.055	1.17	1.40
b	.045	.055	1.14	1.40
b1	.087	.102	2.21	2.59
b2	.111	.126	2.82	3.20
c	.020	.029	0.51	0.74
D	.1020	.1040	25.91	26.42
E	.770	.798	19.56	20.29
e	.215 BSC		5.46 BSC	
L	.780	.820	19.81	20.83
L1	.080	.102	2.03	2.59
Q	.210	.235	5.33	5.97
Q1	.490	.513	12.45	13.03
R	.150	.180	3.81	4.57
R1	.100	.130	2.54	3.30
S	.668	.690	16.97	17.53
T	.801	.821	20.34	20.85
U	.065	.080	1.65	2.03

Ref. IXYS CO 0128 R0

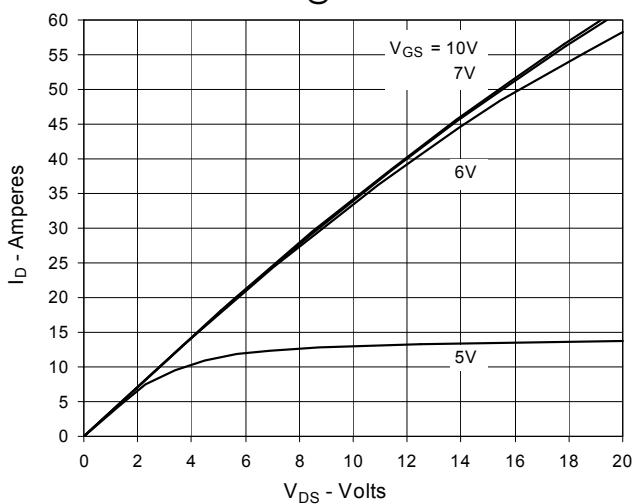
**Fig. 1. Output Characteristics
@ 25°C**



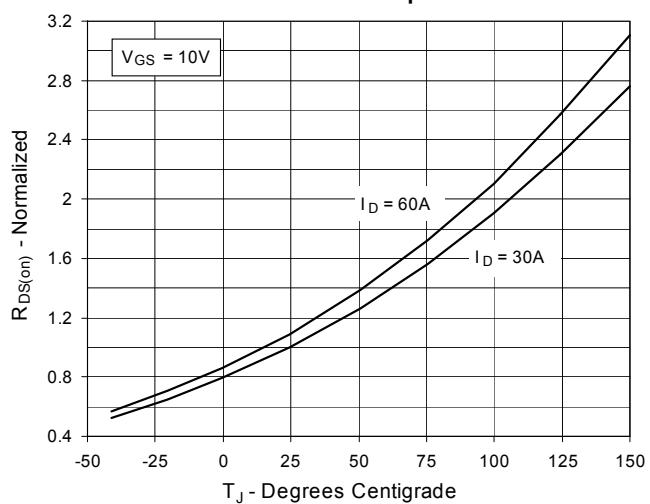
**Fig. 2. Extended Output Characteristics
@ 25°C**



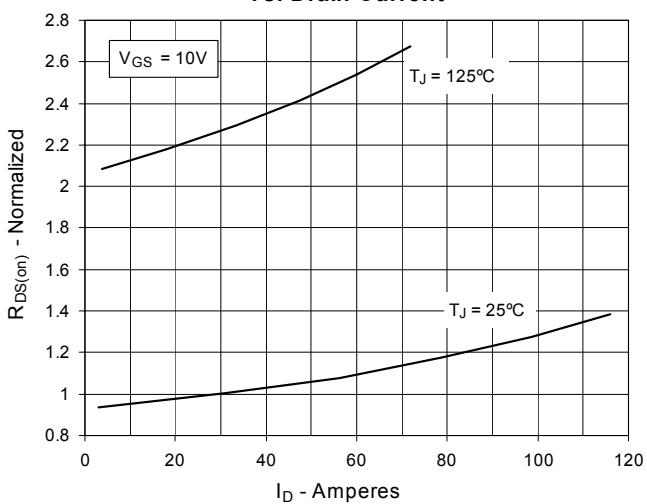
**Fig. 3. Output Characteristics
@ 125°C**



**Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 30A$ Value
vs. Junction Temperature**



**Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 30A$ Value
vs. Drain Current**



**Fig. 6. Maximum Drain Current vs.
Case Temperature**

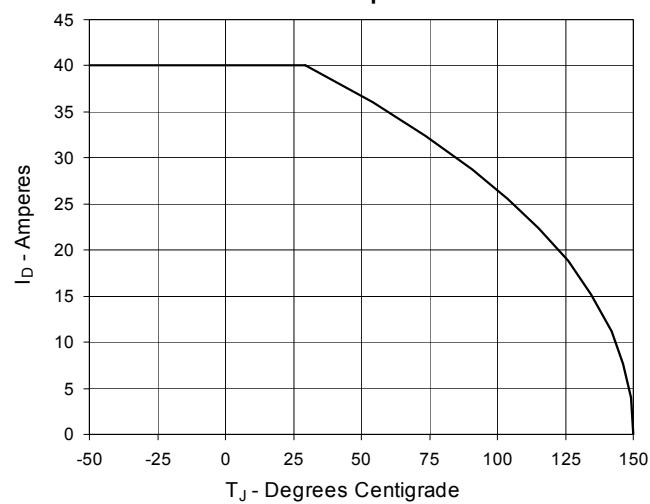
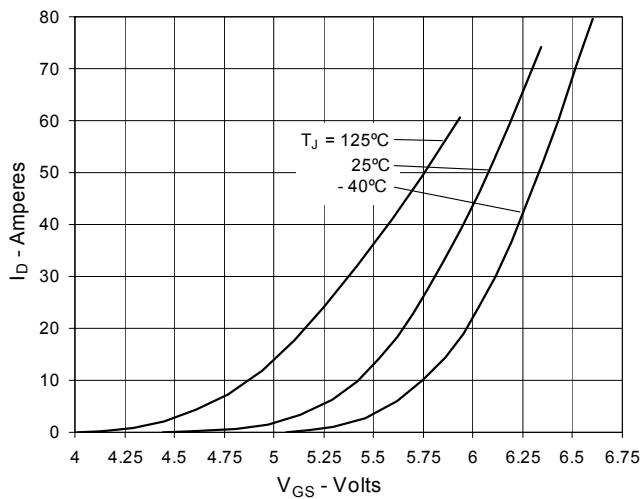
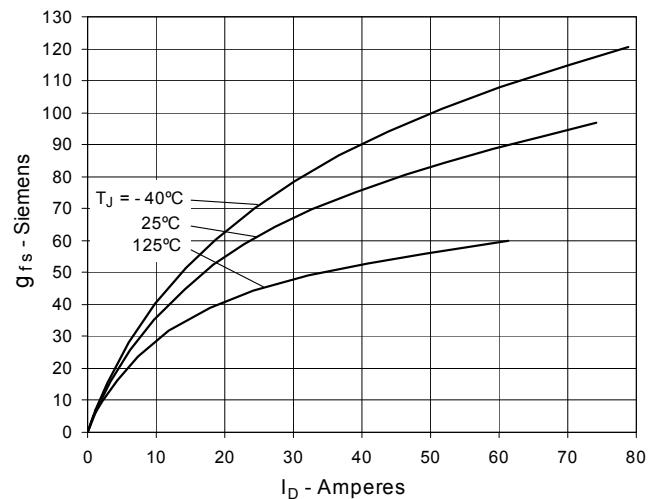
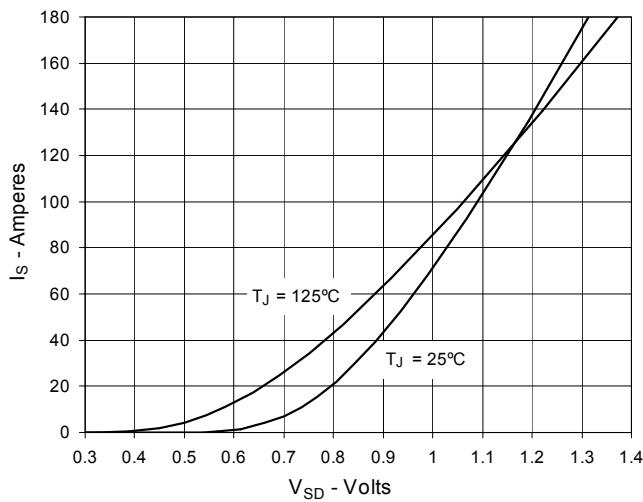
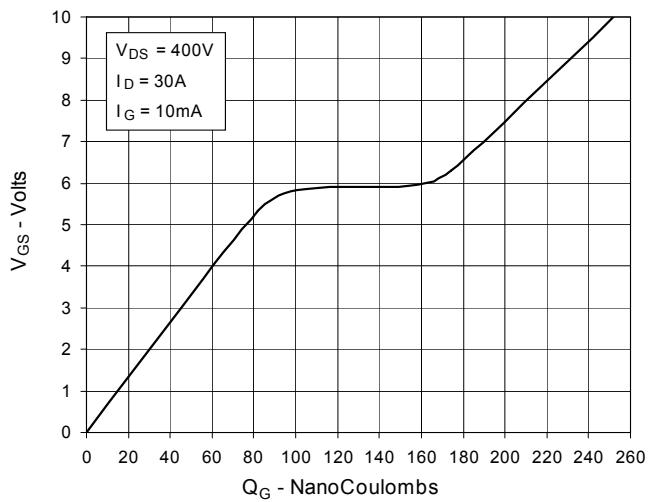
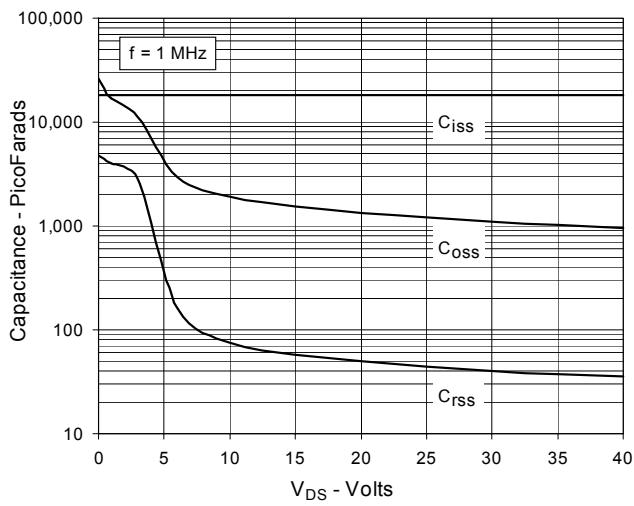


Fig. 7. Input Admittance**Fig. 8. Transconductance****Fig. 9. Forward Voltage Drop of Intrinsic Diode****Fig. 10. Gate Charge****Fig. 11. Capacitance****Fig. 12. Maximum Transient Thermal Resistance**